Yves Fleming

List of Publications by Year in descending order

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933264 887953 23 285 10 17 citations g-index h-index papers 23 23 23 413 docs citations times ranked citing authors all docs

#	Article	IF	CITATIONS
1	Elucidating the growth mechanism of ZnO films by atomic layer deposition with oxygen gas <i>via</i> isotopic tracking. Journal of Materials Chemistry C, 2021, 9, 4307-4315.	2.7	7
2	Critical field anisotropy in the antiferroelectric switching of PbZrO3 films. Applied Physics Letters, 2021, 118, .	1.5	10
3	Design of Silica Nanoparticles-Supported Metal Catalyst by Wet Impregnation with Catalytic Performance for Tuning Carbon Nanotubes Growth. Catalysts, 2021, 11, 986.	1.6	9
4	Resolving cavitation in silica-filled styrene-butadiene rubber composites upon cyclic tensile testing. Polymer Testing, 2021, 100, 107274.	2.3	8
5	Influence of Silica Specific Surface Area on the Viscoelastic and Fatigue Behaviors of Silica-Filled SBR Composites. Polymers, 2021, 13, 3094.	2.0	7
6	Comparison on the structural, mechanical and tribological properties of TiAlN coatings deposited by HiPIMS and Cathodic Arc Evaporation. Surface and Coatings Technology, 2021, 423, 127529.	2.2	23
7	Cavitation Micro-mechanisms in Silica-Filled Styrene-Butadiene Rubber Upon Fatigue and Cyclic Tensile Testing. Advances in Polymer Science, 2020, , 109-129.	0.4	5
8	Controlling electrical and optical properties of zinc oxide thin films grown by thermal atomic layer deposition with oxygen gas. Results in Materials, 2020, 6, 100088.	0.9	17
9	Sodium enhances indium-gallium interdiffusion in copper indium gallium diselenide photovoltaic absorbers. Nature Communications, 2018, 9, 826.	5.8	51
10	Experimental and simulation-based investigation of He, Ne and Ar irradiation of polymers for ion microscopy. Beilstein Journal of Nanotechnology, 2016, 7, 1113-1128.	1.5	22
11	High sensitivity and high resolution element 3D analysis by a combined SIMS–SPM instrument. Beilstein Journal of Nanotechnology, 2015, 6, 1091-1099.	1.5	12
12	Integrated SIMS-AFM Instrument for Accurate High-Sensitivity and High-Resolution Chemical 3D Analysis. Microscopy and Microanalysis, 2015, 21, 1437-1438.	0.2	O
13	Carbon removal from trenches on EUV reticles. , 2014, , .		1
14	Combined SIMS and AFM study of complex structures of streamers on metallic multilayers. Surface and Interface Analysis, 2014, 46, 397-400.	0.8	4
15	SIMS Based Correlative Microscopy for High-Resolution High-Sensitivity Nano-Analytics. Microscopy and Microanalysis, 2014, 20, 966-967.	0.2	2
16	Combined SIMS-SPM instrument for high sensitivity and high-resolution elemental 3D analysis. Surface and Interface Analysis, 2013, 45, 513-516.	0.8	30
17	Differential ion beam sputtering of segregated phases in aluminum casting alloys. Applied Surface Science, 2013, 265, 489-494.	3.1	7
18	Correlative Microscopy Using SIMS For High-Sensitivity Elemental Mapping. Microscopy and Microanalysis, 2013, 19, 356-357.	0.2	2

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#	Article	IF	CITATION
19	Combined SIMS-SPM Instrument for High Sensitivity and High Resolution Elemental 3D Analysis. Microscopy and Microanalysis, 2013, 19, 668-669.	0.2	0
20	Design and performance of a combined secondary ion mass spectrometry-scanning probe microscopy instrument for high sensitivity and high-resolution elemental three-dimensional analysis. Review of Scientific Instruments, 2012, 83, 063702.	0.6	25
21	Combined SIMS-SPM Instrument For High Sensitivity And High Resolution Elemental 3D Analysis. Microscopy and Microanalysis, 2012, 18, 888-889.	0.2	1
22	Three dimensional imaging using secondary ion mass spectrometry and atomic force microscopy. Applied Surface Science, 2011, 258, 1322-1327.	3.1	24
23	Formation of charge-selective Mg–Ag electrodes to CuPc:C60 blend layers. Applied Physics Letters, 2010, 97, .	1.5	18